

An approach for PSL assertion coverage analysis with high-level decision diagrams

Jenihhin, Maksim; Raik, Jaan; Ubar, Raimund-Johannes; Shchenova, Tatjana Proceedings of IEEE East-West Design & Test Symposium (EWDTS'10) : St. Petersburg, Russia, September 17-20, 2010 2010 / p. 13-16 : ill
<https://ieeexplore.ieee.org/document/5742048>

Testing beyond the SoCs in a lego style

Tšertov, Anton; Jutman, Artur; Devadze, Sergei Proceedings of IEEE East-West Design & Test Symposium (EWDTS'10) : St. Petersburg, Russia, September 17-20, 2010 2010 / p. 334-338 : ill <https://ieeexplore.ieee.org/document/5742052>